WEST Search History

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DATE: Friday, April 16, 2004

Hide?	Set Name	Query	Hit Count
		DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ	
☐	L12	L11 and color	38
☐	L11	L10 and mark$	85
☐	L10	L9 and analyz$	147
☐	L9	L6 and type	223
☐	L8	L6 and type of defect	0
☐	L7	L6 and inspection instrument	5
☐	L6	L5 and wafer map	265
☐	L5	defect with wafer	13587
☐	L4	semiconductor defect inspection	29
☐	L3	semiconductor defect inspection instrument	2
☐	L2	5659172.pn. or 5985497.pn. or 6051845.pn. or 6122562.pn. or 6246787.pn. or 6252412.pn. or 6265232.pn. or 6407373.pn. or 6441897.pn.	18
☐	L1	("6524881"|"6559457"|"20030003688A1").PN.	4

END OF SEARCH HISTORY